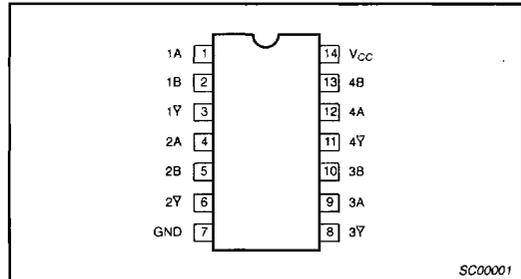


Quad 2-input NAND buffer (open collector)

74ALS38A

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74ALS38A	7.0ns	3.5mA

PIN CONFIGURATION



ORDERING INFORMATION

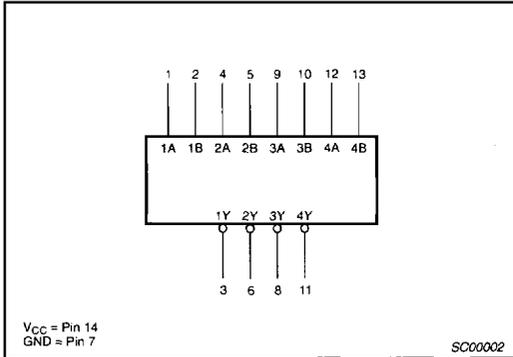
DESCRIPTION	ORDER CODE		DRAWING NUMBER
	COMMERCIAL RANGE V _{CC} = 5V ±10%, T _{amb} = 0°C to +70°C		
14-pin plastic DIP	74ALS38AN	SOT27-1	
14-pin plastic SO	74ALS38AD	SOT108-1	

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

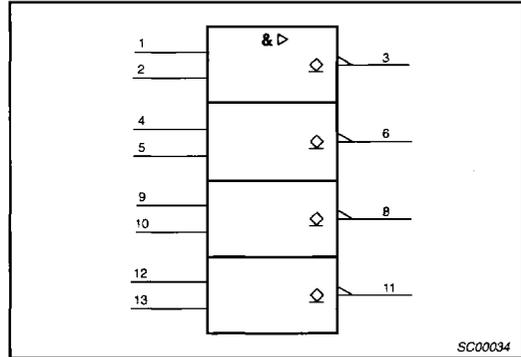
PINS	DESCRIPTION	74ALS (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
nA, nB	Data inputs	1.0/1.0	20µA/0.1mA
nY	Data outputs	20/80	0.4mA/8mA

NOTE: One (1.0) ALS unit load is defined as: 20µA in the High state and 0.1mA in the Low state.

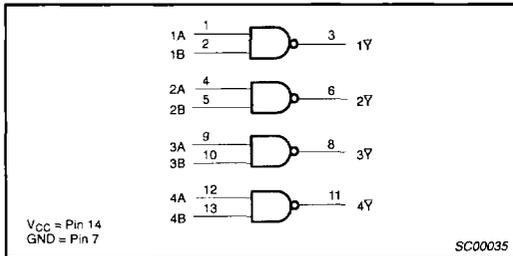
LOGIC SYMBOL



IEC/IEEE SYMBOL



LOGIC DIAGRAM



FUNCTION TABLE

INPUTS		OUTPUT
nA	nB	nY
L	L	H
L	H	H
H	L	H
H	H	L

H = High voltage level
L = Low voltage level
X = Don't care

Quad 2-input NAND buffer (open collector)

74ALS38A

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limit set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage	-0.5 to +7.0	V
V_{IN}	Input voltage	-0.5 to +7.0	V
I_{IN}	Input current	-30 to +5	mA
V_{OUT}	Voltage applied to output in High output state	-0.5 to V_{CC}	V
I_{OUT}	Current applied to output in Low output state	48	mA
T_{amb}	Operating free-air temperature range	0 to +70	°C
T_{stg}	Storage temperature range	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_{IH}	High-level input voltage	2.0			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
V_{OH}	High-level output voltage			5.5	V
I_{OL}	Low-level output current			24	mA
T_{amb}	Operating free-air temperature range	0		+70	°C

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹	LIMITS			UNIT
			MIN	TYP ²	MAX	
I_{OH}	High-level output current	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}, V_{IH} = \text{MIN}, V_{OH} = \text{MAX}$			100	μA
V_{OL}	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}, V_{IH} = \text{MIN}$	$I_{OL} = 12\text{mA}$	0.25	0.40	V
			$I_{OL} = 24\text{mA}$	0.35	0.50	V
V_{IK}	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = I_{IK}$		-0.73	-1.5	V
I_I	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 7.0\text{V}$			0.1	mA
I_{IH}	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7\text{V}$			20	μA
I_{IL}	Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.5\text{V}$			-0.1	mA
I_{CC}	Supply current (total)	$V_{CC} = \text{MAX}$	$V_I = \text{GND}$	0.65	1.6	mA
			$V_I = 4.5\text{V}$	6.5	9.0	mA

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at $V_{CC} = 5\text{V}, T_{amb} = 25^\circ\text{C}$.

Quad 2-input NAND buffer (open collector)

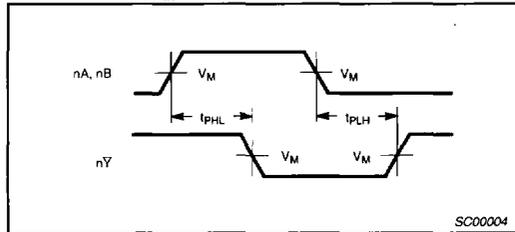
74ALS38A

AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS		UNIT
			$T_{amb} = 0^{\circ}\text{C to } +70^{\circ}\text{C}$ $V_{CC} = +5.0\text{V} \pm 10\%$ $C_L = 50\text{pF}, R_L = 500\Omega$		
			MIN	MAX	
t_{PLH} t_{PHL}	Propagation delay nA or nB to nY	Waveform 1	3.0 3.0	11.0 11.0	ns

AC WAVEFORMS

For all waveforms, $V_M = 1.3\text{V}$.



Waveform 1. Propagation Delay for Data to Output

TEST CIRCUIT AND WAVEFORMS

Test Circuit for Open Collector Outputs

Input Pulse Definition

DEFINITIONS:

- R_L = Load resistor; see AC electrical characteristics for value.
- C_L = Load capacitance includes jig and probe capacitance; see AC electrical characteristics for value.
- R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

Family	INPUT PULSE REQUIREMENTS					
	Amplitude	V_M	Rep.Rate	t_w	t_{TLH}	t_{THL}
74ALS	3.5V	1.3V	1MHz	500ns	2.0ns	2.0ns

SC00036